

# n-channel dual enhancement mode lateral D-MOS FETs

*designed for . . .*



- **Wideband Differential Amplifiers**
- **Cascode High Slew Rate Amplifiers**
- **Single Ended High-Speed Amps**
- **High-Speed Analog Comparators**
- **Sample & Hold Ckts**
- **High-Speed Matched Analog Switches**

#### FEATURES

- High Figure-of-Merit gfs/C
- Ultra Low Feedback Capacitance 0.3 pF
- Low Output Capacitance
- Low Input (Gate) Leakage
- Non-Critical Operating Current/Voltage
- Matched Characteristics

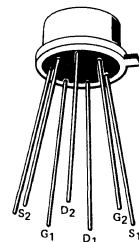
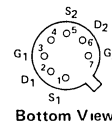
#### BENEFITS

- High Frequency Performance
- High Slew Rate
- High Speed Switching
- Tight Temperature Tracking

#### ABSOLUTE MAXIMUM RATINGS (25°C)

Drain-to-Drain Voltage	±25V
Drain-Source Voltage	+25V
Drain Current	50 mA
Device Dissipation (Each Side), (Derate 3 mW/°C)	367 mW
Total Device Dissipation (Derate 4 mW/°C)	500 mW
Storage Temperature Range	-65 to +200°C
Lead Temperature (1/16" from case for 10 seconds)	300°C

TO-78  
See Section 6



**ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)**

Characteristic	Min	Typ	Max	Unit	Test Conditions
I <sub>GSS</sub> Gate Reverse Current		0.05	1	nA	V <sub>GS</sub> = +15V, V <sub>DS</sub> = 0
BV <sub>DS</sub> Drain-Source Breakdown Voltage	25			V	I <sub>D</sub> = 1 μA, V <sub>GS</sub> = 0
V <sub>GS(th)</sub> Gate-Source Threshold Voltage	0.1	0.8	2.0	V	V <sub>DS</sub> = V <sub>GS</sub> = 10V, I <sub>D</sub> = 1 μA
V <sub>GS</sub> Gate-Source Voltage		1.9	3.0	V	V <sub>DG</sub> = 10V, I <sub>D</sub> = 5 mA
I <sub>G</sub> Gate Operating Current		0.05	1	nA	V <sub>DG</sub> = 10V, I <sub>D</sub> = 5 mA
g <sub>fs</sub> Common-Source Forward Transconductance	7,000	9,000	15,000	μmhos	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0, f = 1 KHz
g <sub>os</sub> Common-Source Output Conductance		20	100	μmhos	
R <sub>DS(ON)</sub> Drain-Source Resistance			60	Ω	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 10V
C <sub>iss</sub> Common-Source Input Capacitance		3.2	5	pF	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0, f = 1 MHz
C <sub>rss</sub> Common-Source Reverse Transfer Capacitance		0.5	1.2	pF	

Characteristic	SD2110		SD2120		Unit	Test Condition
	Min	Max	Min	Max		
M A T C H I N G   V <sub>GS1</sub> = V <sub>GS2</sub>   Differential Gate-Source Voltage		10		20	mV	V <sub>DG</sub> = 10V, I <sub>D</sub> = 5 mA  T <sub>A</sub> = 25°C T <sub>B</sub> = 125°C T <sub>A</sub> = -55°C T <sub>B</sub> = 25°C
Δ V <sub>GS1</sub> - V <sub>GS2</sub>   Gate-Source Differential Drift <sup>3</sup>		25		50	μV/°C	
ΔT		25		50	μV/°C	
g <sub>fs1</sub> Transconductance Ratio <sup>2</sup>	0.95	1	0.95	1		f = 1 KHz
g <sub>fs2</sub>						

**NOTES:**

1. Pulswidth ≤ 300 μs, duty cycle ≤ 3%.
2. Assumes smaller value in numerator.
3. Measured at end points, T<sub>A</sub> and T<sub>B</sub>.